From D iscrete H opping to C ontinuum M odeling on V icinal Surfaces with A pplications to Si(001) E lectrom igration

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C carse-grained m odeling of dynam ics on vicinal surfaces concentrates on the di usion of adatom s on terraces with boundary conditions at sharp steps, as rst studied by Burton, C abrera and Frank (BCF). Recent electrom igration experiments on vicinal Si surfaces suggest the need for more general boundary conditions in a BCF approach. We study a discrete 1D hopping m odel that takes into account asym metry in the hopping rates in the region around a step and the nite probability of incorporation into the solid at the step site. By expanding the continuous concentration eld in a Taylor series evaluated at discrete sites near the step, we relate the kinetic coe cients and perm eability rate in general sharp step m odels to the physically suggestive parameters of the hopping m odels. In particular we nd that both the kinetic coe cients and perm eability rate can be negative when di usion is faster near the step than on terraces. These ideas are used to provide an understanding of recent electrom igration experiment on Si(001) surfaces where step bunching is induced by an electric eld directed at various angles to the steps.

I. IN TRODUCTION

Steps on vicinal crystal surfaces, created by a m iscut along a low index plane, have long been of great interest in both basic and applied research.¹ H igh quality crystals can be grown through step- ow | the uniform motion of m ore or less equally-spaced steps | and step bunching instabilities can create arrays of wide at terrace separated by closely bunched steps. O ther arrangements of steps could serve as tem plates for nanoscale structures and devices.

M ost fundam ental studies of the static and dynam ic properties of vicinal surfaces are based on generalizations of the classic theory of Burton, C abrera, and Frank (BCF), developed m ore than fly years ago.² This theory describes the di usion of adatom s on terraces with boundary conditions at steps, which are treated as sharp line boundaries. O riginally BCF assumed that the steps acted as perfect sinks and sources of adatom s so that the lim iting adatom concentration at the step boundaries always reduces to local equilibrium.

M any extensions and m odi cations of the BCF theory have been suggested to provide a m ore general fram ework for the description of di erent experiments. One of the m ost important was Chemov's introduction of linear kinetic coe cients, which permit deviations from local equilibrium at steps.^{3,4} It was soon recognized that in general the kinetic coe cients could be asym m etric. ⁵ A nother generalization permits step permeability or transparency, with a term in the boundary condition directly connecting the limiting adatom concentration on adjacent terraces.⁶ T hese generalized BCF m odels provide a m esoscopic or coarse-grained description of surface evolution with e ective boundary conditions at sharp steps, and we will generally refer to them as sharp step models.

M any kinetic instabilities seen in experiments have been successfully described from this perspective using various combinations of boundary conditions. However in general it is not clear how to connect the choices and values of the e ective parameters in sharp step models to the underlying physical processes or how to determ ine the uniqueness of such a mapping. A similar di culty arises in trying to relate \m icroscopic" parameters in kinetic M onte C arb simulations of discrete hopping m odels to the e ective parameters in a generalized sharp step m odel. Very di erent m icroscopic m odels can som etim es seem to give equally plausible m esoscopic descriptions of limited sets of experimental data.

In previous work⁷ we proposed a novel continuum tworegion di usion m odel (CTRM), which gave a rather sim – ple and uni ed description of a variety of current-induced instabilities seen experimentally on vicinal Si surfaces. We will discuss these experiments in more detail later. The m odel assumes that di usion rates in a nite region around a step could be a ected by the dierent local bonding con gurations and thus dier from those found elsewhere on terraces. By extrapolating the steady state concentration pro les to the center of the step region, we obtained a mapping of the parameters in the CTRM to those of an equivalent classical sharp step m odel. O ne surprising conclusion was that negative kinetic coe cient can arise when the di usion rate near a step is faster than that on the terraces.

In this paper, we will provide a more system atic way of deriving the boundary conditions for the continuum sharp step models from a rather general 1D discrete hopping model that perm its both asym metric di usion in the step region as well as step permeability. As discussed by



FIG.1: A schem atic plot of the 1D potential surface near an atom ic step. D i erent D's that have dimensions of di usion constants characterize the hopping rates associated with different barrier heights. Here, we take the width of the step region to be 2a.

G hez and Iyer,⁸ such an e ective 1D model can result from averaging over relevant 2D con gurations of kink and ledge sites on an atom ic step. We then use these ideas to provide a detailed description of electrom igration on Si(001) surfaces, and nd a coherent scenario that explains most of the interesting experimental ndings.

II. 1D HOPPING MODEL

The simple 1D model that we study is schematically shown in Fig. 1, where an atom ic step site is surrounded by a region of width s with generally di erent di usion rates, induced by reconstruction or rearrangements of bcal dangling bonds. As we will see, this di erence can generate e ective kinetic coe cients in a sharp step description.

In general, the width s of the step region with di erent di usion barriers should vary for di erent systems. However, we nd that the essential physics of the hopping model is not strongly a ected by speci c choices of s of order of a few lattice spacings a. Thus we analyze the algebraically simplest case shown in F ig. 1 with half-step regions of width a. The more general result, needed in the analysis of Si(001) experiments, is easily obtained by replacing a with s=2, as will become clear later when we com pare the results of this generic hopping model to our previous results.

W e include here two additional physical features of the step region as illustrated in Fig. 1. One is the possible asymmetry in the di usion processes in the up and down half-step regions, described by hopping rates D = a: The D have dimensions of a di usion constant, and the model is usefully characterized by dimensionless parameters

$$R \qquad D = D_t; \qquad (1)$$

with D $_{\rm t}$ the di usion constant on the terraces.

The other feature we build in is step permeability or transparency, characterized in our model by a single pa-1). This can be understood as ram eter p_k (0 R the e ective probability in our 1D m odel that an adatom hopping to site 0 will encounter a kink site at a given tem perature and thus equilibrate with the solid. This param eter takes account of e ects from both kink site density and ledge diusion in a full 2D model. When $p_k = 1$, the step site acts as a perfect sink maintained by either enough kink sites or fast ledge di usion or both, and consequently the step site concentration will be pinned at equilibrium c_{eq} . In the opposite lim it with $p_k = 0$ no adatom s are incorporated into the solid. The step site behaves like any other terrace site and thus is perfectly perm eable. W e neglect other possible sources of perm eability, including direct hopping over the step region from one terrace to another or e ects of rapid step motion,⁹ which we believe are less physically relevant for our cases of interest. In this section we will also consider only diffusion uxes from concentration gradients, and discuss the case of driven diusion from an external eld in the Appendix.

W e assume that the net ux of adatom s that hop between step site 0 and site a can be partitioned into two e ective contributions:

$$J_{a=2} = \frac{D_{+}}{a} [p_k fc_{eq} \hat{c}(a)g + (1 p) f\hat{c}(0) \hat{c}(a)g];$$
(2)

The rst term describes an adatom exchange with probability p_k involving equilibrated \kink-like" adatom s at site 0 with density c_{eq} and the neighboring terrace site. The second term involves a similar exchange with probability $(1 \ p_k)$ involving unincorporated \ledge-like" adatom s with density c(0): Only the form er involves creation/annihilation of adatom s, and the latter is treated as a norm aldi usion ux that conserves the adatom density.

Similarly, the ux from site a to 0 is

$$J_{a=2} = \frac{D}{a} [p_k f \hat{c} (a) g_q g + (1 p_k) f \hat{c} (a) \hat{c} (0) g];$$
(3)

Since we assume that all the sinks/sources reside only at site 0, the net ux of adatom s that hop from site a (2a) to site 2a (a) takes on the simpler form

$$J_{3a=2} = \frac{D_t}{a} [c(a) c(2a)]:$$
 (4)

As in m any other situations of physical interest, we will use the quasi-static approximation to simplify the analysis. Here we assume that the motion of the step region is much slower than the relaxation of the terrace di usion eld, so that one can determ ine the di usion process on

terrace sites with xed positions of the step regions. In the quasi-static lim it the net change in the number of adatom s at each terrace site given by a total ux balance m ust vanish, i.e., $d\hat{c}(x) = dt = 0$ for all x = a; 2a ::: In particular, at sites a, the balance of uxes is given by

$$0 = \frac{d\hat{c}(a)}{dt} = aJ_{a=2} \quad aJ_{3a=2} :$$
 (5)

At step site 0, $\hat{c}(0)$ can be determined by balancing the conserved ux term sproportional to $(1 p_k)$ in Eqs. (2) and (3), and is given by

$$\hat{c}(0) = \frac{D_{+}\hat{c}(a) + D_{-}\hat{c}(-a)}{D_{+} + D};$$
(6)

III. RELATING PARAMETERS IN DISCRETE AND CONTINUUM MODELS

O ur task now is to relate the physically suggestive param eters R and p_k in the discrete hopping model to the kinetic coe cients k and permeability rate P appearing in the boundary conditions of a continuum sharp step model as in Eq. (7) below. For x > 0, consider a smooth continuum concentration pro lec (x) that passes through the discrete concentrations $\hat{c}(a)$ and $\hat{c}(2a)$. (The caret distinguishes discrete from continuum functions.) The behavior of c (x) at larger x is determined by the physical processes on the terraces, but does not need to be specied explicitly for our purposes here.

To make contact with the sharp step model, we rewrite the uxes in Eqs. (2)-(5) in term $\operatorname{sofc}(x)$. To that end we use a Taylor series expansion to linear order to express $c(a) = \hat{c}(a)$ and $c(2a) = \hat{c}(2a)$ in term $\operatorname{sofc}^+ c(0)$; the extrapolated limiting concentration as $x \, ! \, 0^+$ at the sharp step edge in a continuum picture, and its associated gradient r c j. Similarly, $\hat{c}(a)$ and $\hat{c}(2a)$ can be expressed in term sofc and r c j, which in generalare di erent than c^+ and r c j.

U sing Eq. (6) to elim inate \hat{c} (0); and substituting into Eq. (5), we nd that the result can be rewritten in the form of a generalized linear kinetics boundary condition⁸ with permeability

$$D_t r c j v c = k c c_q + P c c : (7)$$

The kinetic coe cients k are given by

$$k = \frac{D_{t}}{a} \frac{p_{k}}{(R \ 1) [1 + (1 \ P)M]}; \qquad (8)$$

where

$$M = \frac{R_{+}R_{-}}{(R_{+}+R_{-})} \frac{R_{+}}{R_{-}1} + \frac{R_{-}}{R_{+}1}$$
(9)

is symmetric on exchange of + and : Note in general that the ratio of the kinetic coe cients satis es

$$\frac{k_{+}}{k} = \frac{R}{R_{+}} \frac{1}{1}$$
(10)

independent of p_k : The permeability rate P can be written as

$$P = \frac{k}{p_{k} (R - 1)} \frac{(1 - p_{k}) R_{+} R_{-}}{(R_{+} + R_{-})} :$$
(11)

U sing Eq. (8) in the rst factor, we see that P is symmetric on exchange of + and , and has a nite limit as $p_k \ ! \ 0 \ :$

The nalparam eter v in Eq. (7) is zero in our present treatment since we used the quasi-static approximation to derive Eqs. (5) and (6). In principle, a non-vanishing v would arise if we took the ux due to step motion into account in the discrete hopping model. However, the quasi-static limit is valid in most physical cases of interest, and thus this additional complication can be avoided.

Equations (7-11) are the central results in this section. A sm entioned earlier, we nd that the sharp step boundary condition can indeed be generally expressed using linear kinetics with permeability. More importantly, we are able to relate the elective parameters in the sharp step boundary conditions to the physically suggestive parameters we considered in our generic hopping model. This mapping provides a simple way to understand many aspects of electrom igration phenomena on Si surfaces.

A notable general feature of these equations is that the kinetic coe cients k are proportional to p_k and the permeability rate P is proportional to $(1 \ p_k)$. The kinetic coe cients characterize adatom exchange involving equilibrated solid adatoms at kinks and the adatom gas phase, while the permeability rate characterizes adatom motion across the step without equilibrating with the solid phase. Moreover, the kinetic coe cients k are in general asymmetry of emission and di usion processes from kinks. However, the permeability rate P is symmetric since the physical processes of hopping from one side to the other without attachment at the step always involves the di usion constants on both sides.

We now consider some limits of the above general expressions to illustrate some interesting features of both the kinetic coe cients and the permeability rate.

A. Im perm eable steps, $p_k ! 1$

This limit is usually considered in treatments of the sharp step model, and we used it to analyze current-induced instabilities on Sisurfaces.⁷ In this limit the only way for the adatom s to go across a step is through attach-ment/detachment at kinks, and the permeability rate P vanishes.

The results are conveniently described in terms of the attachment/detachment lengths

Using Eq. (8), these are given by

$$d = a(R 1)$$
: (13)

If we replace the width 2a of the step region in the present m odel by a general value s, we recover exactly the results we found earlier⁷ using the CTRM . As shown in the appendix, Eq. (13) also holds to low est order even when there is an external driving eld that a ects processes in the step region.

This shows the general validity of the mapping between model parameters that we found earlier by considering di usion driven by a weak electric eld. For R > 1, corresponding to slower di usion in the step region, the attachment/detachment lengths and kinetic coe cients are positive. The kinetics is usually called attachment/detachment limited when d l, with 1 the average terrace width in a uniform step train, ordi usion limited when 0 d l. For R = 1, d vanishes, and the kinetic coe cients diverge. This forces c to equal c_{eq} in Eq. (7) and generates the local equilibrium boundary condition originally proposed in the BCF m odel.

M ore interestingly, for R < 1, corresponding to faster di usion in the step region, the attachm ent/detachm ent lengths and the corresponding kinetic coe cients are negative. A swe showed earlier,⁷ the sign of the kinetic coefcients plays a key role in interpreting electrom igration experim ents on Sisurfaces, since it determ ines the stability of a uniform step train for a given current direction. T his application of our general results will be discussed in m ore detail below.

In the following, we will characterize the limit $p_k ! 1$ as denning a perfect sink model, since adatoms can not di use across a step without attachment/detachment at kink sites. As a direct consequence, the two sides of the step are decoupled and any change of the microscopic rates on one side of the step does not a ect the kinetic coe cient on the other side. However, as shown above, the two sides of the step will in general be coupled for $p_k < 1$ through Eqs. (10) and (11), and the subsequent analysis of step dynamics become smuch more involved.

B. Very perm eable steps, p_k ! 0

This limit may be physically relevant at low enough temperatures, or slow enough ledge di usion, or some proper combination of both. Here the adatoms hop around on the surface without encountering sinks/sources in the step region. Thus one expects vanishing kinetic coe cients, but a nite permeability rate, and this is indeed what Eq. (8) and Eq. (11) predict in this limit.

As in Eq. (12), let us de ne a corresponding perm eability length

$$d_{\rm P} \qquad D_{\rm t}=P: \tag{14}$$

Then Eqs. (11) and (8) yield

$$d_{\rm P} = 2a \ \frac{1}{2} (R_+ + R_-) \ 1$$
: (15)



FIG. 2: P lot of the dimensionless permeability length $d_P = a$ as a function of R in the symmetric case for a general p_k .

Similar to d ; the permeability length d_P can become negative when $(R_+ + R_-) < 2$, with faster di usion in the step region. Eq. (15) is consistent with results derived from a continuum phase eld model.⁹ Recently P ierre-Louis and M etois¹⁰ have argued that negative permeability lengths can explain some novel grow th-induced instabilities seen during electrom igration on Si(111) surfaces.

C . Partially perm eable steps, $0 < \, p_k < \, 1$

This is the most general case, where only a nite fraction of adatom s at the step equilibrate at kinks, presum – ably corresponding to interm ediate tem peratures with moderate ledge di usion. We focus on the sim plest sym – metric case where $D = D_s$ or $R_+ = R = R$ in Eqs. (8)-(11). The attachment/detachment length becomes

$$d = \frac{a}{p_k} (R \quad p_k); \qquad (16)$$

and the perm eability length is

$$d_{\rm P} = 2a ({\rm R} \ 1) \frac{({\rm R} \ {\rm R})}{(1 \ {\rm R}) {\rm R}}$$
 (17)

Equation (16) can be understood using the same physics as in the perfect sink model. W ith a nite probability p_k to encounter a kink, an adatom has to move faster in the step region ($D_s = D_t = p_k$) to maintain local equilibrium (d ! 0 or k ! 1) compared with the perfect sink case ($D_t = D_s$). The permeability length in Eq. (17) is a new feature arising from the possibility that the adatom s go directly across the step w ithout equilibrating with the solid. This expression show sa fairly com plicated dependence on m icroscopic motions characterized by R and p_k .

A schem atic plot of d_P versus R for a given p_k is shown in Fig. 2. Both d and d_P diverge as R ! 1, since all motion in the step region vanishes in this limit. d_P decreases as R decreases, and stays positive for R > 1. Just like the attachm ent/detachm ent length, the perm eability length changes sign from positive to negative as R passes through 1, with equal hopping rates in the terrace and step regions. However, the perm eability length becomes positive again for sm allenough R when the motion in the step region is su ciently fast ($R < p_k$) that the probability of crossing the step without involvement of a kink is e ectively decreased to a point that it is no longer faster than hopping on terraces.

IV. APPLICATIONS TO ELECTROM IGRATION ON SI(001)

We now apply these ideas to current-induced instabilities on vicinal Si surfaces.¹¹ Step bunching is seen on Si(111) surfaces when the electric current is properly directed norm al to the step direction.¹² The uniform step train is initially stable when the current ows in the opposite direction. There are three tem perature ranges between about 850 C and 1300 C where the stable and unstable directions are reversed. However, at sim ilar tem peratures vicinal Si(001) surfaces m iscut along [110] exhibit step bunching from current norm al to the steps in both directions.^{14,15} C haracteristic bunching patterns have also been observed for current directed at various angles to the steps.¹⁶

There is general agreement that in the presence of an electric eld adatom s acquire an electric charge z e (which includes both electrostatic and a \wind-force" contribution arising from scattering of charge carriers), and thus experience a eld-directed force F = z eE that biases their di usive motion. However, it is less clear what are appropriate boundary conditions in a sharp step model for these processes and how they might be a ected by the electric eld and by surface reconstruction. The generic hopping model studied in Sec. II helps us shed som e light on these issues, and the results can be applied to electrom igration on both Si(111) and Si(001) surfaces. In this paper we discuss applications to Si(001) surfaces. The di erent Si(111) instabilities will be discussed elsewhere.¹⁷

The most notable di erences in current-induced step bunching on Si(001) and Si(111) surfaces arise from the (2 1) surface reconstruction (dimerization) on Si(001), which persists up to temperatures of at least 1200 C .¹⁸ Two characteristic directions on the surface are established by dimerization, either parallel or perpendicular to the substrate dimer rows in the orthogonal [110] direction, denoted by k and ? respectively. Experimental evidence suggests that the di usion along the dimer rows s is much faster at low temperatures, i.e., D $_{\rm t}^{\rm k}$ D $_{\rm t}^{2}$.¹⁹

In recent experiments,¹⁶ the bunching behavior was studied on dimple geometries, where steps of all orientations are found. As schematically shown in Fig. 3a, there are in general two angles needed to describe the local geometry of the dimple when the electric eld is applied,¹⁶ characterized by the angle between direction



FIG. 3: A schematic illustration of the dimple geometry on the Si(001) surface. (a) The general view of the dim ple with the crystallographic directions indicated above. Zoom ing into a given local area of the dim ple (the dotted line box), we show the step-terrace con guration with a general direction of the electric eld. ' is the angle between eld direction and the local norm al to the steps, while is the angle between the eld and [110]. = =4 corresponds to a eld direction along [010]. (b) The top view of the dim ple when = 0. Zoom ing into the dotted-lined box near the center of the dim ple with ' = 0, we show a top view of the vicinal surface and a side view of the step-terrace con guration. Most of basic physics of step pairing and bunching will be illustrated in this sim ple 1D geometry with the electric eld perpendicular to average step position.

of the electric eld and the [110] direction, and the angle ' between the eld and the local norm alto the steps.

The bunching exhibits interesting angular dependences. W hen the current is parallel to the orthogonal [110] direction (= 0), the bunching is observed to be strongest in the areas where the current is locally parallet to the step norm ald irection (' = 0), e.g., the dotted line box in Fig. 3b. No bunching occurs in the corresponding perpendicular directions (' = -2). How ever, if the current is rotated to =4 o the dim er row direction (==4), the strongest bunching occurs in the areas where the current is perpendicular to the local step directions (' = = 2). No bunching is seen in the corresponding perpendicular direction (' = 0), which in the previous case was where the maximum bunching was found. In the following discussion, we will rst study the instabilities for the simplest case as shown in the dotted line box in Fig. 3b (= 0 and \prime = 0), and then generalize our results to arbitrary and '.

A. Dom ain Conversion and Step Pairing

Let us begin with the simplest case, where the vicinal surface is m isoriented in the [110] direction. At equilibrium rather straight S_A steps that run parallel to the dimer rows of the upper A terrace alternate with much

rougher S_B steps that run perpendicular to the dimerrows of the upper B terrace.²⁰ W hen the eld is normal to the steps, as illustrated in the boxed region of Fig. 3b, the terrace di usion rates normal to the steps satisfy $D_t^B = D_t^A$. We assume that the dimerization persists at least to some extent on both adjacent half-step regions around each terrace and will similarly a ect di usion rates there. The normal di usion in the two half-step regions around a given step is characterized by D_s^A and D_s^B . Taking account of the di erences in terrace di usion rates, it seems reasonable to assume at least that D_s^B .

$$D_t^B D_t^A D_s^B D_s^A 0$$
: (18)

Special cases of this assumption include classical local equilibrium steps where $R^{A} = R^{B} = 1$ and a symmetric step model where $D_{s}^{B} = D_{s}^{A}$.

The assumption here essentially states that the fundam ental physics on Si(001) surfaces is dominated by the alternating reconstruction domains on terraces. Under this assumption, it is natural to think of the surface as m ade up of alternating A and B units, where the unit (= A or B) contains an terrace together with the

two neighboring half step regions.

We consider here cases where the system is driven away from equilibrium only by the electric eld. We make the usual assumption that permeability does not play an essential role in this case and take the limit p_k ! 1 for simplicity. We also neglect evaporation and assume a positive electrice charge. The perfect sink limit decouples the concentration elds on the terraces, and permits a simple solution to the steady state di usion problem in terms of exponential functions e^{fx} , where f F $\hat{x}_{\overline{E}} kT$.

In alm ost all cases of experimental interest, the eld is su ciently weak that fs fl_t 1, where s and l_t are the width of the step and terrace regions, and we obtain piecew ise linear pro les for the adatom concentration. It is then straightforw and to write down the general solution for the adatom density in unit as

$$C (x) = \begin{cases} 8 \\ \gtrless \\ c_{eq} + m_{s} \\ c_{eq} + m_{t} \\ \vdots \\ c_{eq} + m_{s} \\$$

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where l_t is the terrace width. In the above expression the origin is set at the center of the terrace region to take m axim um advantage of sym m etry. It is easy to transform the origin to the left atom ic step position in accordance with the previous discussion on hopping m odels, and the results below will not be altered by any speci c choice of the coordinate system.

The $m_{s,t}$ can be obtained by requiring continuity of concentration and ux at 1=2 and are given by

$$n_t (l_t) = c_{eq} sf (R \quad 1) = (l_t + R \quad s)$$

 $\begin{array}{ll} m_{s} \left(l_{t}\right) = c_{eq}l_{t} \mbox{ f} \left(1 \quad R \mbox{ }\right) = \left(l_{t} + R \mbox{ s}\right) \eqno(20)\\ \mbox{H ere } R \quad D_{t} = D_{s} \mbox{ gives a dimensionless }m \mbox{ easure of the relative di usion rates in the unit between the terrace and step regions in a direction perpendicular to the step direction, and <math display="inline">c_{eq}$ is the average concentration for a uniform step array when f=0.

In the quasi-static approximation the step velocities are computed by a ux balance. The surface ux normal to the step is constant throughout the unit and is exactly given by

$$J_{0} = D_{t} C_{eq} f \frac{l_{t} + s}{l_{t} + R s} :$$
 (21)

Because of the perfect sink assumption, the uxes in the individual units on either side of a step are independent of each other. Thus the step velocity is easy to compute for a given step con guration.

Consider in particular the initial velocity of step S in a uniform step train $(l^A_t$ = l^B_t = l_t). This is given by

$$v_{0} = J_{0} \quad J_{0} \qquad h \qquad i$$

$$= c_{eq}f (l_{t} + s) \frac{D_{t} \quad D_{t} \quad l_{t} + D_{s} \quad D_{s} \quad sR \ R}{(l_{t} + R \ s) \ (l_{t} + R \ s)}$$
(22)

where i = A or B and is the atom ic area. In

this case the velocities of the two types of steps satisfy

 $v_0^B =$ v. Therefore the initial uniform step array is not a steady state. Depending on the direction of the electric eld, one reconstruction dom ain expands while the other shrinks, creating step pairs separated by the m inor terrace. With a downhill current one nds double height D_B steps (consisting of an upper S_B step and a low er S_A step with a narrow A terrace trapped in between) separated by wide B terraces; the equivalent con guration with D_A steps and narrow B terraces is seen for an uphill current. Experiments show that this eld-driven step pairing continues until it is balanced at short distances, probably by step repulsions, as rst suggested by N atori. et al,²¹ in the special case where local equilibrium was assumed for all the steps, corresponding to $R^{A} = R^{B} = 1$ in our model.

B. Continued Bunching of Paired Steps

Now let us exam ine the stability of arrays of such paired steps. A ssum ing that the step pairs (boundaries of the m inor dom ain) with constant spacings persist throughout the bunching process, as is shown by experiments, we can de ne a symmetric elective two-region model that can describe the continued bunching of the paired steps. To that end, we treat the m inor reconstruction terrace together with the two step regions bounding it as an elective step region that separates one m a jor terrace from another, as schematically shown in Fig. 4 for the case of a step-down current. As shown below (and previously discussed⁷), the bunching behavior is determined by the eld direction and the sign of the kinetic coelist cient for the sharp step model associated with the elective two-region model de ned here.

In the Appendix we discuss the mapping to a sharp step model from a 1D hopping model that treats the effects of the electric eld explicitly, while assuming there is a perfect sink at x = 0 in the center of the step region. In the present case a minor terrace resides at the center of the electric step region. We can still follow basic treatment in the Appendix if we take this into account by shifting the origin of the coordinate system by transform ing x ! x (1 + s) =2 and s=2 ! $1^0=2+s$, where 1^0 is the width of the minor reconstruction domain. Representing the discrete terrace concentrations by a continuum function c (x) and Taylor expanding as before about x = 0^+ | the center of the electrice step region | we nd that the electrice sharp interface boundary condition takes a form analogous to Eq. (A 5):

where D_t , = A or B, is the norm ald i usion constant in the major terrace. The continuum prole is schematically depicted in Fig. 4 for the case of a step-down current.

Two new features are seen in Eq. (23) arising from the use of a single e ective step region to describe the paired steps. First, the major terrace is determined by the current direction in the initial step pairing regime. Second,



FIG.4: A schematic illustration of extrapolation for an elective step region. W ith a step-down current, domain (1 2) expands to form an elective terrace region with some typical concentration pro le c_t . On the other hand, domain (2 1) shrinks to 1^0 and form s an elective step region when combined with the two step regions bounding it. c_t is extrapolated to the dotted-dashed line at x = 0 in the middle of the minor terrace which represents the elective \sharp" step.

both an e ective kinetic coe cient k and an e ective \equilibrium concentration" c_{eq} appear in the sharp step boundary condition. The latter is given by

$$c_{eq} = c_{eq} \ 1 \ \frac{1}{2}f \ (1^0 + s)$$
 : (24)

This can be understood heuristically by noting that the e ective density in the center c_{eq} should be linearly modied by the weak eld from its value c_{eq} at the \real" local equilibrium step near the lower boundary of the e ective step region. Sim ilarly, the e ective attachment length d associated with the e ective kinetic coe cient k is given by

d
$$\frac{D_t}{k} = \frac{s}{2} R - 1;$$
 (25)

where $s = 1^0 + 2s$ is the width of the elective step region and R = sR =s is the relative di usivity in the elective two region model de ned above.

Equations (23)-(25) give the mapping between the effective two region model describing paired steps separated by major terraces and an equivalent sharp step model. In the steady state where the major terraces all have the same width, the surface ux in the sharp step model can be obtained from Eq. (21) as follows. We replace the parameters c_{eq} , s, and R by the corresponding elective parameters c_{eq} , s, and R. Clearly $l = l_t + s$ represents the terrace width in the sharp step model. The steady state ux in the sharp step model can be obtained from Eq. (21) as follows.

the terrace width is thus given by

$$J_0 (l) = D_t c_{eq} f \frac{l}{l+2d}$$
: (26)

Note that = A or B is determined by the current direction.

To exam ine the stability of the above steady state, consider a small deviation $x_n = "_n e^{!t}$ of the nth step in the uniform step train, where $"_n = "e^{in}$. Here " is a small constant and is the phase between neighboring steps. Then the nth step will move in response to the unbalanced ux induced by the changed widths of the terraces in front $l_n = 1 + "_n (e^i \quad 1)$ and back $l_{n-1} = 1 + "_n (1 \quad e^i)$. The linear ampli cation rate $! = v_n = "_n$ is given by

$$! = D_{t} c_{eq} \frac{4d f}{1+2d^{2}} (1 \cos): \qquad (27)$$

An instability towards step bunching results if d f > 0with a maximum at = , corresponding to step pairing. Note that the direction of the eld and the sign of the e ective kinetic coe cient combine to determ ine when step bunching occurs, as discussed earlier.⁷

Using Eqs. (25) and (27), we see that to get simultaneous step bunching from current in both directions, as seen in experiment, requires

$$R^{A} > 2 + \frac{1^{0}}{s} > R^{B}$$
: (28)

W ith a step-down current, the rst part of the inequality in Eq. (28) makes the elective kinetic coel cient for the elective step region containing the slower dilusion domain positive, which results in a step bunching instability. The second inequality in Eq. (28) give rise to a negative elective kinetic coel cient which produces step bunching with a step-up current. Note that this does not require negative kinetic coel cients for single steps of either kind.

However, if one assumes the individual steps are at local equilibrium, ($\mathbb{R}^{\mathbb{A}} = \mathbb{R}^{\mathbb{B}} = 1$), then the kinetic coe cient for the elective step region is negative in both cases, and therefore bunching is expected only from a step-up current.

C. A ngular D ependence

It is straightforw and to extend the above analysis to a general dimple geometry, where the domain conversion exhibits interesting angular dependences. A schematic view of the experimental dimple is shown in Fig. 3a. A gain, we need to consider the uxes from the neighboring terraces going into the step. U sing Eq. (21), we can represent the surface ux as the sum of uxes along the two characteristic directions,

$$J_{f} = \cos J_{0}^{B} k + \sin J_{0}^{A} b$$
(29)

for the front terrace and

$$J_{\rm b} = \cos \ J_0^{\rm A} \stackrel{\rm b}{\cdot} + \sin \ J_0^{\rm B} \stackrel{\rm b}{\star} \tag{30}$$

for the back terrace of step 1 in Fig. 3a, where k and ? are the directions parallel and perpendicular to dim er rows as de ned earlier. The angular dependent step velocity is readily obtained

$$v_0^{(1)}$$
 (;') = v_0^{B} cos (2 '); (31)

where v_0^B is given by Eq. (22). Eq. (31) shows that a steady state of paired steps will form on the part of the dim ple where $\cos(2 \quad \prime) \in 0$.

In the following, we will concentrate on two special congurations that are studied experimentally.¹⁶ The rst is shown in Fig. 3b, where the current is parallel to the dimerrow direction. In this case = 0, and cos' characterizes the angular dependence around the dimple. The maximum pairing instability occurs at ' = 0 where the current is perpendicular to the step norm aldirection, and no instability in seen at ' = =2. From the previous discussion in Sec IV A and Sec IV B, we can easily see that continued step bunching occurs with a maximum at ' = 0.

The other interesting con guration corresponds to an upright eld parallel to [010] direction in Fig. 3a. In this case the current is at an angle = =4 from the dim er row direction. Hence the angular dependence becomes $\cos(=2$ ') = \sin' . The maximum pairing instability occurs at ' = =2, where the current is parallel to the steps, and no instability occurs when the current is perpendicular to the steps. Again the sharp step m odel corresponding to the steady state can be extracted. The subsequent step bunching instability for a parallel current was discussed by Liu et al.²² Their stability analysis suggests that step bunching generally occurs for a non-vanishing attachm ent/detachm ent length d, regardless of its sign, when the current is parallel to the average step positions.

The results discussed here are in good agreement with experiments. For the angular dependent step pairing, the result is consistent with the original analysis by N ielsen et al.¹⁶ H ow ever, our explanation for the subsequent step bunching is di erent. Our analysis provide a simpler scenario that does not require a tensor character to the effective charge.

V. CONCLUSION

This paper derives expressions for sharp step boundary conditions characterized by linear kinetics rate param eters k and P for general BCF type models by appropriate coarse-graining from a microscopic hopping model. k and P are related to the attachment/detachment kinetics at kinks and to di usion across the ledges respectively. In particular, our study shows that both param eters can be negative when di usion is faster in the step region than on terraces. The possibility of negative kinetic coe cients was rst suggested by Politi and V illain, 23 but with no derivation or discussion of any physical consequences. In the appropriate limit, we recover the mapping previously obtained with the CTRM.⁷ Our results also seem consistent with those from phase eld models,⁹ while providing a simple and physically suggestive picture.

We then used the perfect sink limit ($p_k = 1$) of the general model to analyze current-induced instabilities on Si(001), where the eld represents the only driving force away from equilibrium, and found results in good agreement with experiment. As we will show elsewhere, this same limit also provides a coherent interpretation of Si(111) electrom igration experiments, where novel step w andering behavior is seen.¹⁷ Thus we believe that the perfect sink model provides a simple and physically reasonable description of many electrom igration experiments on vicinal Si surfaces.

A cknow ledgm ents

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APPENDIX A:1D PERFECT SINK MODEL W ITH A CONSTANT ELECTRIC FIELD

In the generic hopping m odel discussed earlier, we assum ed that the ux arose only from concentration graIn the absence of the eld, the 1D potential energy surface is similar to that in Fig. 1, where now the site at x = 0 is a perfect sink surrounded by a more general region of width s with di erent di usion barriers. When a weak electric eld is applied in the positive x direction, the potential energy surface will be modi ed by an amount V = F dx, where F = z eE, z e is the e ective charge. The modi cation of the potential surface produces a bias for adatom hopping, which will later lead to a convective ux contribution in the continuum description.

The driven ux inside the step region can be written as

$$J_{x+a=2} = \frac{D_{s}}{a} e^{fa=2} c_{s} (x) \qquad \frac{D_{s}}{a} e^{fa=2} c_{s} (x+a); \quad (A1)$$

where f $f = k_B T$. The quasi-static approximation suggests continuity of uxes, i.e. $J_{x+a=2} = J_{x=a=2}$, which leads to the following equation for the discrete concentration $c_s(x)$,

$$0 = e^{fa=2} c_{s} (x + a) \qquad e^{fa=2} + e^{fa=2} c_{s} (x) + e^{fa=2} c_{s} (x - a);$$
(A2)

where x is evaluated at discrete lattice sites inside the step region. It is easy to write down the solution of Eq. (A 2) as

$$C_{s}(x) = C_{eq} + A e^{Ix} 1;$$
 (A3)

taking account of the perfect sink at x = 0. Here A is a constant that can be determined by continuity of uxes at the boundary between step and terrace region, i.e. $J_{s=2}_{s=2} = J_{s=2+a=2}$. This gives

$$A = \frac{e^{fa=2} R c_{t} \frac{s}{2} + a}{e^{fa=2} e^{fs=2}} \frac{e^{fa=2} + e^{fa=2} (R - 1) c_{eq}}{1 R + e^{fa=2} e^{fa=2}};$$
(A 4)

Here \hat{c}_t is the discrete concentration on the terrace site.

To obtain the sharp interface boundary condition, we apply ux continuity $J_{s=2+\;a=2}$ = $J_{s=2+\;3a=2}$, and express

all the discrete terrace concentrations in term s of the extrapolated c^{\dagger} and the corresponding gradient r c j . In the weak eld lim it that is valid in most experiments, we can linearize the exponentials in all of the above expressions. To the leading order, we obtain the boundary condition as

$$D_t rcj fc = k c c_q : (A5)$$

where results for both the + and sides can be given by symmetry. Note that the term proportional to f is the convective ux induced by the eld, which is of the same order as the concentration gradient. A sm entioned earlier in Section III, the mapping to the kinetic coe cient is independent of the eld to low est order, and is given by

d
$$\frac{D_{t}}{k} = \frac{1}{2}$$
 (R 1) s; (A 6)

where R $D_t=D_s$. Equation (A 6) recovers the results we derived earlier from CTRM, and is also consistent

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